

was stirred for 12 h and the solvent removed in vacuo to yield the crude product. Clear crystals of pure **2** were obtained by slow cooling of a hot saturated toluene solution. Anal. Calcd for $\text{GeC}_{40}\text{H}_{38}\text{N}_2\text{O}_2$ (**2**): C, 73.72; H, 5.87; N, 4.29. Found: C, 71.60; H, 5.78; N, 3.62. ^1H NMR (C_6D_6 , 30 °C): δ 1.51 (s, NMe_2), 6.8–7.5 (aromatics).

Sn(OAr')₂(NMe₂)₂ (3**).** To a stirred solution of $\text{Sn}(\text{NMe}_2)_4$ (0.50 g, 1.70 mmol) in benzene (10 cm^3) was added dropwise a solution of 2,6-di-*tert*-butyl-4-methylphenol (HOAr', 0.75 g, 3.4 mmol) in benzene (10 cm^3). The resulting clear, bright yellow solution was stirred for 12 h before the solvent was removed in vacuo. The crude yellow product was taken up in the minimum amount of hot hexane and the solution slowly cooled to yield large yellow crystals. Anal. Calcd for $\text{SnC}_{34}\text{H}_{58}\text{N}_2\text{O}_2$ (**3**): C, 63.26; H, 9.05; N, 4.34. Found: C, 59.67; H, 9.41; N, 3.89. ^1H NMR (C_6D_6 , 30 °C): δ 1.47 (s, Bu^t), 2.25 (s, *4-Me*), 2.36 (s, SnNMe_2 , $^2J(^{119}\text{Sn}-^1\text{H}) = 74$ Hz), 6.91 (s, *m-H*).

Crystallographic Studies. Selected crystallographic data are collected in Table VIII. The data collection and refinement were carried out by using the routine procedures adopted by the Purdue Chemistry Department Crystallographic Center. A suitable crystal of each of the three compounds was examined under deoxygenated Nujol and mounted in an

appropriately sized glass capillary surrounded by epoxy resin. In the case of **3** a 10% loss of intensity of standards was observed during data collection and a linear correction was applied. For the germanium compounds **1b** and **2** no decay was observed and no correction for estimation was applied. For the tin compound **1** an empirical absorption correction was applied. The positions of the hydrogen atoms were calculated by assuming idealized geometry and a carbon-hydrogen bond distance of 0.95 Å. For the methyl groups, one hydrogen was located in a difference Fourier map. This position was idealized, and the remaining positions were calculated. No hydrogen atoms were refined. For compound **2** the other enantiomorph yielded $R = 0.044$ and $R_w = 0.055$ with $\text{GOF} = 1.788$ so that the enantiomorph reported here is correct.

Acknowledgment. We thank the National Science Foundation (Grant CHE-8915573) for support of this research.

Supplementary Material Available: Tables of crystallographic data, thermal parameters, full bond distances and angles, and hydrogen positional and thermal parameters (34 pages); listings of observed and calculated structure factors (57 pages). Ordering information is given on any current masthead page.

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Polymeric Xenon Materials: $(-\text{Xe}-\text{O}-\text{TeF}_4-\text{O}-)_n$. Crystal Structure of $\text{HF}\cdot\text{HO}-\text{TeF}_4-\text{O}-\text{Xe}^+\text{AsF}_6^-$

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XeF_2 reacts with *cis*-(HO)₂ TeF_4 to form a yellow, insoluble polymer $(\text{XeO}_2\text{TeF}_4)_n$ that is stable to about 80 °C. Reaction of *cis*-(HO)₂ TeF_4 with $\text{XeF}_2^+\text{AsF}_6^-$ affords a material of the composition $\text{FXe}-\text{O}-\text{TeF}_4-\text{O}-\text{Xe}^+\text{AsF}_6^-$. Recrystallization of this in anhydrous HF affords a crystalline material $\text{HF}\cdot\text{HO}-\text{TeF}_4-\text{O}-\text{Xe}^+\text{AsF}_6^-$. According to its crystal structure ($a = 504.74$ (4), $b = 758.93$ (5), $c = 1387.25$ (7) pm; $\alpha = 90.14$ (5), $\beta = 95.74$ (5), $\gamma = 99.67$ (6)°; $P\bar{1}$; $Z = 2$) the coordination number of xenon is closer to 1 than in any other known xenon compound.

Introduction

Substitution chemistry on xenon fluorides, even on the most stable xenon difluoride, is limited to ligands with high electronegativity. Greatest stability has been observed with the oxygen ligands $-\text{OTeF}_5$ and $-\text{OSeF}_5$, less so with $-\text{OSO}_2\text{F}$ and others.¹ Nitrogen ligands are so far limited to the $-\text{N}(\text{SO}_2\text{F})_2$ and $-\text{N}(\text{SO}_2\text{CF}_3)_2$ groupings and a few members of the *S*-triazine family.²⁻⁴ Compounds that have nitrogen donor functions to xenon such as $[\text{FXe}-\text{NCH}_3]^+$ or $[\text{FXe}-\text{NC}-\text{CH}_3]^+$ have been prepared recently also.⁵ The bonding to carbon is even more limited. While $\text{Xe}(\text{CF}_3)_2$ has never been fully characterized,⁶ there is now clear evidence for the existence of the $^+\text{Xe}-\text{C}_6\text{F}_5$ cation including a crystal structure.^{7,8}

Reaction of XeF_2 with bidentate ligands poses a challenge, since bidentate ligands having enough electronegativity are very limited.

The most stabilizing ligand in xenon-oxygen chemistry, $-\text{OTeF}_5$, is derived from HOTeF_5 , which in turn is a member of a series $(\text{HO})_n\text{TeF}_{6-n}$. All these compounds $(\text{HO})_n\text{TeF}_{6-n}$ for $n = 1-5$ have been shown to exist,⁹⁻¹¹ but only $\text{HO}-\text{TeF}_5$ and *cis*- and *trans*-(HO)₂ TeF_4 have been isolated in pure form.^{12,13} Of these, *cis*- and *trans*-(HO)₂ TeF_4 are here of special interest. *cis*-(HO)₂ TeF_4 is somewhat more acidic than *trans*-(HO)₂ TeF_4 ,¹⁴ and a number of covalent derivatives such as $(\text{ClO})_2\text{TeF}_4$, $(\text{BrO})_2\text{TeF}_4$, and $[(\text{CH}_3)_3\text{SiO}]_2\text{TeF}_4$ have already been described with both *cis* and *trans* configurations.¹² The intermolecular anhydride $\text{F}_4\text{TeO}_2\text{TeF}_4$ and the anion *cis*- $\text{O}_2\text{TeF}_4^{2-}$ in $\text{Na}_2\text{O}_2\text{TeF}_4$ are also known.¹⁵

Results

We reported in a short communication that *cis*-(HO)₂ TeF_4 reacts with XeF_2 with the formation of HF, whereas *trans*-(HO)₂ TeF_4 does not react under the same conditions, possibly a consequence of its somewhat lower acidity. The product between

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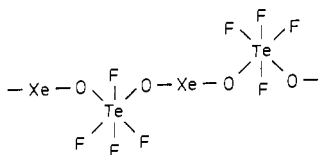
Table I. Crystallographic Data for HF·HO-TeF₄-O-Xe⁺AsF₆⁻

AsF ₁₁ H ₂ O ₂ TeXe	MW 576.8
<i>a</i> = 504.74 (4) pm	<i>P</i> 1̄ (No 2)
<i>b</i> = 758.93 (5) pm	<i>T</i> = -156 °C
<i>c</i> = 1387.25 (7) pm	<i>λ</i> = 170.69 pm
<i>α</i> = 90.14 (5)°	<i>ρ</i> (calcd) = 3.675 g·cm ⁻³
<i>β</i> = 95.74 (5)°	<i>μ</i> = 94.1 cm ⁻¹
<i>γ</i> = 99.67 (6)°	<i>R</i> = 4.2%
<i>V</i> = 521.1 × 10 ⁶ pm ³	<i>R_w</i> = 4.3%
<i>Z</i> = 2	

Table II. Atomic Parameters for HF·HO-TeF₄-O-Xe⁺AsF₆⁻ (Standard Deviations in Parentheses)

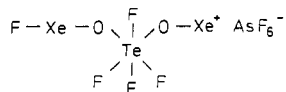
atom	<i>x</i>	<i>y</i>	<i>z</i>
Xe	0.1267 (1)	0.2631 (1)	0.1278 (1)
As	0.3961 (2)	0.2338 (2)	-0.1236 (1)
Te	0.2785 (2)	0.2576 (1)	0.3751 (1)
F	0.0339 (22)	0.7251 (11)	0.3717 (7)
F1	0.3630 (17)	0.0748 (10)	0.3032 (6)
F2	0.4698 (17)	0.1859 (10)	0.4823 (6)
F3	0.5837 (15)	0.3929 (10)	0.3370 (6)
F4	-0.0232 (15)	0.1040 (10)	0.4022 (6)
F11	0.6156 (16)	0.3277 (10)	-0.0269 (6)
F12	0.6276 (16)	0.2954 (11)	-0.2037 (7)
F13	0.1534 (15)	0.1344 (9)	-0.2145 (6)
F14	0.2770 (17)	0.4302 (9)	-0.1398 (6)
F15	0.4990 (16)	0.0318 (10)	-0.1049 (6)
F16	0.1552 (15)	0.1704 (10)	-0.0402 (6)
O1	0.0737 (18)	0.3315 (12)	0.2601 (7)
O2	0.1915 (21)	0.4408 (13)	0.4439 (7)

XeF₂ and *cis*-(HO)₂TeF₄ is a faintly yellow solid of the analytical composition (XeO₂TeF₄)_n, which is insoluble in all common solvents. It decomposes above 80 °C with evolution of xenon and oxygen, leaving behind a colorless solid that is mostly TeF₄ according to mass spectroscopy. Since the Raman spectrum contains a typical Xe-O stretching vibration at 455.5 cm⁻¹ as well as TeF and TeO stretching vibrations (610–778 cm⁻¹), we concluded that the material is a polymer such as

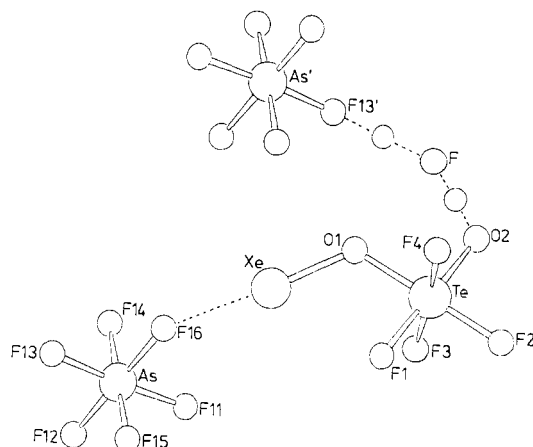


Structural principles require the linearity of the xenon environment and the *cis* configuration around tellurium.

In order to isolate smaller units of this polymer, we have tried to vary the synthetic route. Replacing XeF₂ by Xe₂F₃⁺AsF₆⁻ afforded a compound of the composition Xe₂F₃O₂TeF₄AsF₆. This is a stable yellow solid that is insoluble in chlorofluorocarbons or SO₂Cl₂, decomposes at -70 °C in SO₂ and at -40 °C in CH₃CN, but dissolves readily in HF. The Raman spectrum of the solid shows a very strong band at 484.5 cm⁻¹, which is assigned as *ν*_{XeO}, a band at 677 cm⁻¹, attributable to *ν*₁ of AsF₆⁻, and bands at 641, 667, and 762 cm⁻¹ (*ν*_{TeF} and *ν*_{TeO}). The structure of the material may well be



The only known compound that it may be compared with is [FXe-O-SOF-O-XeF]⁺AsF₆⁻. This is formed by reacting FXe-OSO₂F with AsF₅.^{16,17} Here, however, confirmation of the molecular structure was finally done by X-ray crystallography.¹⁸ Yellow solutions of FXe-O-TeF₄-O-Xe⁺AsF₆⁻ in liquid HF show a ¹²⁵Te NMR spectrum of the A₂B₂ or A₂BC type and a single,

**Figure 1.** View of HF·HO-TeF₄-O-Xe⁺AsF₆⁻. A second AsF₆⁻ is included to show the bridging through the HF molecule. The proton positions have not been obtained crystallographically but are drawn in assumed positions.**Table III.** Bond Distances (pm) and Angles (deg) (Standard Deviations in Parentheses)

Distances			
Xe-F16	245.8 (8)	As-F16	177.1 (7)
Xe-O1	196.2 (9)	Te-F1	183.8 (7)
As-F11	172.2 (8)	Te-F2	182.6 (8)
As-F12	170.2 (8)	Te-F3	182.8 (7)
As-F13	174.2 (7)	Te-F4	182.7 (7)
As-F14	170.6 (7)	Te-O1	194.9 (9)
As-F15	171.2 (7)	Te-O2	182.1 (9)
Angles			
F11-As-F12	92.4 (4)	F1-Te-F2	90.3 (3)
F11-As-F13	175.1 (4)	F1-Te-F3	86.2 (4)
F11-As-F14	90.2 (4)	F1-Te-F4	87.4 (4)
F11-As-F15	90.8 (4)	F1-Te-O1	89.2 (3)
F11-As-F16	87.5 (4)	F1-Te-O2	178.7 (4)
F12-As-F13	92.5 (4)	F2-Te-F3	91.1 (4)
F12-As-F14	90.8 (4)	F2-Te-F4	90.5 (4)
F12-As-F15	92.2 (4)	F2-Te-O1	179.4 (3)
F12-As-F16	179.8 (1)	F2-Te-O2	91.0 (4)
F13-As-F14	89.5 (4)	F3-Te-F4	173.4 (4)
F13-As-F15	89.3 (4)	F3-Te-O1	89.1 (4)
F13-As-F16	87.6 (4)	F3-Te-O2	93.6 (4)
F14-As-F15	176.8 (4)	F4-Te-O1	89.2 (4)
F14-As-F16	89.1 (4)	F4-Te-O2	92.8 (4)
F15-As-F16	87.9 (4)	O1-Te-O2	89.6 (4)
Xe-F16-As1	133.0 (4)	F16-Xe-O1	175.6 (3)
Te-O1-Xe	123.3 (4)		

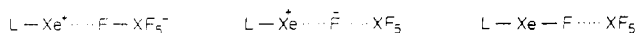
broad ¹²⁹Xe resonance, while the ¹⁹F NMR resonance is largely obscured by the intense and broad HF signal. Cooling the solutions in HF afforded yellow platelike crystals that evolve HF at +5 °C, while the remaining solid is ill-defined. The crystal structure (at -156 °C) of this crystalline material is shown in Figure 1; see also Tables I–III. The formula HF·HO-TeF₄-O-Xe⁺AsF₆⁻ was clearly established, the homologous compound to the known F₃Te-O-Xe⁺AsF₆⁻, which has been determined spectroscopically.^{19–21}

Obviously solvolysis has occurred with HF. The molecule HF·HO-TeF₄-O-Xe⁺AsF₆⁻ exhibits a few features that need comment. The shape of the molecule consisting of a *cis*-O₂TeF₄ fragment and of a single coordinated xenon atom is obvious. The latter point is remarkable: Crystal structures of xenon(II) cations are known, e.g. XeF⁺Sb₂F₁₁⁻,²² XeF⁺AsF₆⁻,²³ and others. In these

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cases xenon is bonded closer to the remaining fluorine atom than in XeF₂, while there is a secondary contact to one of the fluoride atoms from the anion in a linear geometry. It has been established that the longer this "bridging" linear cation-anion contact, the shorter is the bonding between xenon and the covalently bonded fluorine.



The left formula represents the ionic case, the middle the bridging situation, and the right a molecular adduct such as XeF₂·IF₅.²⁴ All structurally characterized derivatives of xenon lie within the two extreme bonding situations. HF·HO-TeF₄-O-Xe⁺AsF₆⁻ represents the case closely approaching the pure ionic case as in the left formula.

The Xe⁺·F-AsF₆⁻ contact is 245.8 pm, as compared to 234.0 pm in XeF⁺Sb₂F₁₁⁻ and 221.2 ppm in XeF⁺AsF₆⁻. Also, the special As-F bond length of the "bridging" fluorine atom is 177.1 pm, only ≈7 pm longer than the shorter AsF bond lengths. In XeF⁺AsF₆⁻ this difference is about 13.3 pm. On the other hand, the Xe-O bond length is markedly shorter (196.2 pm) than in other xenon(II)-oxygen species (216 pm in F-Xe-O-SO₂F),²⁵ 212 pm in F₃Se-O-Xe-OSeF₃).²⁶

A closer look shows that the xenon-bonded O-Te bond is slightly longer than the hydrogen-bonded O-Te bond. Obviously the strong participation of the first oxygen in the xenon-oxygen bond decreased its ability for bonding toward tellurium. The HF molecule bridges the tellurium center with another AsF₆⁻, since there is a contact between the hydrogen atom and a fluorine atom on arsenic. This special As-F bond is also very little (≈3 pm) longer than the four shorter As-F bonds. The Xe⁺·F contact can therefore be described just a little stronger than this H⁺·F contact.

Experimental Section

Spectra. Infrared spectra were obtained on a Perkin-Elmer 883 infrared spectrophotometer, either on gases, pressure 1–10 Torr, or on mulls in either halocarbon or mineral oil; the window material most commonly used was KCl. Raman spectra were taken on a Cary 82 instrument using an Ar laser for excitation (Spectra-Physics). Mass spectra were obtained on either a Varian 711 or MAT 112S high-resolution mass spectrometer using a solid inlet probe. Only the most important ions are reported. The mass numbers are given for ¹³⁰Te. The intensities include all isotopes. The ¹⁹F and ¹H NMR spectra were recorded on a JEOL FX 90Q nuclear magnetic resonance spectrometer using CCl₃F and (CH₃)₄Si, respectively, as external standards. Resonances appearing upfield from CCl₃F in the ¹⁹F NMR spectra are designated negative. The ¹²⁵Te and ¹²⁹Xe were recorded on a JEOL FX 90Q NMR spectrometer using (HO)₆-Te/H₂O and XeOF₄ as external standards. Elemental analyses were obtained from Beller Microanalytical Laboratory in Göttingen, West Germany.

Reagents. XeF₂,²⁷ Xe₂F₃⁺AsF₆⁻,²⁸ and (CH₃)₃Si-O-TeF₅²⁹ were prepared according to literature methods. All other reagents were taken from laboratory stock and were purified, where necessary, before use.

Preparation of cis-[(H₃C)₃SiO]₂TeF₄. Isomerically pure material is formed by the following procedure: A 117.5-g (0.38-mol) sample of (H₃C)₃Si-OTeF₅, 67.2 g (0.42 mol) of O[Si(CH₃)₃]₂, and 0.5 mL of H₂O are refluxed at 100 °C for 132 h. The reflux condenser is held at 30 °C in order not to condense the (H₃C)₃SiF formed in the reaction. Every 24 h another 0.5 mL of H₂O is added. Distillation on a spinning-band column (30-cm length) at normal pressure gives unreacted [(H₃C)₃Si]₂O at 100 °C and then unreacted (H₃C)₃Si-OTeF₅ at 37–38 °C/100 mbar. The final product at 87 °C/20 mbar is 97.4 g (67% yield) of cis-[(CH₃)₃SiO]₂TeF₄ as a colorless liquid, mp -10 °C. ¹⁹F NMR

(neat): a₂b₂ pattern, δ_a = -28.0 ppm, δ_b = -35.1 ppm, J_{ab} = 161 Hz, J(¹²⁵Te-F) = 3391 Hz. ¹H NMR (neat): δ = 0.56 ppm. IR (liquid): 2985 (w), 1765 (w), 1400 (m), 1264 (s), 940 (w), 895 (m), 855 (m), 768 (m), 695 (s), 680 (w), 500 cm⁻¹ (vw). Raman (liquid): 2966 (21, dp), 2906 (69, p), 1417 (14, dp), 1263 (10, p), 939 (21, p), 857 (12, p), 766 (19, dp), 695 (6, dp), 683 (78, p), 639 (100, p), 613 (41, p), 495 (71, p), 357 (9, p), 326 (10, p), 311 (13, p), 268 (6, p), 251 (16, p), 226 (3, p), 199 (3, p), 162 cm⁻¹ (6, p). Anal. Calcd for C₆H₁₈Si₂O₂TeF₄: C, 18.87; H, 4.71; Te, 33.42; F, 19.89. Found: C, 18.60; H, 4.49; Te, 33.02; F, 19.70.

Preparation of cis-(HO)₂TeF₄. A 25-g (65.5-mmol) sample of cis-[(H₃C)₃Si-O]₂TeF₄ is placed into a Teflon FEP reaction vessel, and 10.5 g (575 mmol) of anhydrous HF is condensed into the reactor by using a stainless steel vacuum line. The mixture is stirred at 50 °C for 48 h. At 0 °C the volatile materials HF and (H₃C)₃SiF are pumped off. The solid residue is sublimed at room temperature under vacuum onto a -5 °C finger. A 14.9-g amount (96% yield) of cis-(HO)₂TeF₄ is obtained as a colorless, crystalline solid, mp 106 °C. ¹⁹F NMR (acetone-d₆): a₂b₂ pattern, δ_a = -33.1 ppm, δ_b = -41.8 ppm, J_{ab} = 154 Hz. ¹H NMR (acetone-d₆): δ = 11.14 ppm. IR (Nujol): 3600–3490 (m, br), 1625 (w), 1100–1000 (m), 730 (m), 720 (vw), 680 (vw), 650 (vw), 630 (vw), 330 cm⁻¹ (m). Raman (solid): 731 (12), 711 (5), 679 (100), 646 (11), 635 (5), 317 (51), 186 cm⁻¹ (18). Anal. Calcd for H₂O₂TeF₄: H, 0.84; Te, 53.71; F, 31.97. Found: H, 1.17; Te, 51.87; F, 31.2.

Preparation of (-Xe-O-TeF₄-O)_n. A 1-g (5.6-mmol) sample of XeF₂ is weighed into a Teflon FEP reaction vessel. Also 1.4 g (5.9 mmol) of cis-(HO)₂TeF₄ contained in a smaller FEP tube is placed into the vessel, so that no mixing occurs. In vacuo, 10 mL of anhydrous n-C₄F₉-SO₂F is condensed at -196 °C into the reaction vessel. The two solid starting materials are mixed by shaking at room temperature. After 1/2 h of stirring, all volatile materials are pumped off. The residue contains 2.0 g (92% yield) of faintly yellow (-Xe-O-TeF₄-O)_n, 80 °C dec. Raman (solid): 917 (1), 778.5 (15), 725 (5), 662.5 (12), 610 (13), 455.5 (100), 392.5 (10), 286 (2), 230 (10, sh), 220 (22), 118 cm⁻¹ (75). Anal. Calcd for XeO₂TeF₄: Xe, 35.8; Te, 34.8; F, 20.7. Found: Xe, 34.9; Te, 35.1; F, 20.8.

cis-FXeO-TeF₄-O-Xe⁺AsF₆⁻. In a glovebox 3.2 g (6.3 mmol) of Xe₂F₃⁺AsF₆⁻ was weighed into a FEP reactor. Also a Teflon FEP tube containing 1.5 g (6.3 mmol) of cis-(HO)₂TeF₄ is placed into the reactor as in the experiment above. With use of an all-metal vacuum line and liquid-nitrogen cooling, 15 mL of anhydrous HF is condensed into the reactor. The Xe₂F₃⁺AsF₆⁻ is dissolved in HF at -78 °C, and then, by shaking, the cis-(HO)₂TeF₄ is mixed with the solution. After being slowly warmed to 0 °C, the mixture is kept at 0 °C until a clear, light yellow solution is obtained. All volatiles are pumped off until no more loss of weight is observed. A 3.8-g amount (86% yield) of a light yellow solid is obtained, mp 89 °C dec. The solid is stable at room temperature; however, it is very moisture sensitive. ¹²⁵Te NMR (HF): δ = -82.5 ppm, J(¹²⁵Te-F) = 3502, 3519 Hz. ¹²⁹Xe NMR (HF): δ = -913 ppm. Raman (solid): 762 (s), 667 (m), 641 (s), 603 (w), 484.5 (vs), 426.5 (s), 380 (m), 360.5 (m), 317.5 (m), 304 (m), 275.5 (s), 226 (w), 174.5 (s), 144.5 (s), 98.5 (vs), 83.5 cm⁻¹ (vs). Anal. Calcd for Xe₂O₂TeAsF₁₁: F, 29.6; As, 10.6; Te, 18.1; Xe, 37.2. Found: F, 32.3; As, 11.6; Te, 19.6; Xe, 36.7.

Crystal Structure of HF·HO-TeF₄-O-Xe⁺AsF₆⁻. Keeping FXeO-TeF₄-O-Xe⁺AsF₆⁻ for prolonged time in liquid, anhydrous HF at -35 °C afforded orange crystals. Under dry nitrogen a platelike crystal of 0.6 × 0.5 × 0.2 mm size was mounted at a temperature below -100 °C on the tip of a goniometer and cooled to -156 °C. A description of the technique employed for selecting and mounting the crystal can be found in ref 30. The crystal structure was solved with direct methods and refined with SHELX. All atoms were finally refined anisotropically. Hydrogen positions were assumed; see Figure 1. DIFABS was used for an absorption correction. For further experimental data, see Table II. The results of the crystal structure determination are collected in Tables I–III and Figure 1.

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Supplementary Material Available: Listings of full experimental conditions and anisotropic temperature factors (2 pages); a table of observed and calculated structure factors (10 pages). Ordering information is given on any current masthead page.

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